Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/682,314	BELLM ET AL.	
Examiner	Art Unit	_
Hwei-Siu C. Payer	3724	

Hwei-Siu C. Payer

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Class	Subclass	Date	Examiner
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	43.6	10-17-05	Payer
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INT	INTERFERENCE SEARCHED				
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Interop	rence se	auch hist	WY		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
"PLUS" search conducted by STIC	10-11-05	Pager		